INFORMATION
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Applicant(s): Ryota Nanjo et al

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Group Art Unit: Not Yet Assigned

NOW I 3 tree 5			U.S. PATENT DOCUMENTS				
Examina Initial	AT & TRAD	Socument No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
JMJ	AA	5,956,603	Talwar et al	9/21/99	438	520	
	AB						

FOREIGN PATENT DOCUMENTS

		Document No.	Date	Country	Translation (Yes or No)
JMJ	AF	2001-007220	1/12/01	JP	Yes, abstract
	AG	2000-269491	9/29/00	JP	Yes, abstract
	AH	2000-196037	7/14/00	JP	Yes, abstract
	ΑI	07-231044	8/29/95	JP	Yes, abstract
	AJ	06-053157	2/25/94	JP	Yes, abstract
JMJ	AK	05-067776	3/19/93	JP	Yes, abstract_

OTHER DOCUMENTS

JMJ	AL	"Activation and Deactivation of Laser Thermal Annealed Boron, Arsenic, Phosphorus and Antimony Ultra-Shallow Abrupt Junctions", Murto et al; TH-13; Ion
1m1	AM	Implantation Technology 2000 "Self-Aligned Nickel-Mono-Silicide Technology for High-Speed Deep
		Submicrometer Logic CMOS USI", Morimoto et al; Vol 42, No. 5, May 1995 IEEE, pp 915-923.
<u>IMI</u>	AN	"70nm MOSFET with Ultra-shallow, Abrupt, and Super-doped S/D Extension
<u>IM J</u>	AO	Implemented by Laser Thermal Process (LTP); Bin Yu et al; 1999 EEE 7 "Front End Processes"; International Technology Roadmap for Semiconductors 1999; pp 105-141
Examiner	IM	Date Considered 10-30-03 \$